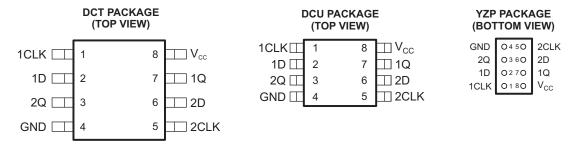
SCES536C-DECEMBER 2003-REVISED JANUARY 2007

FEATURES

- Available in the Texas Instruments
 NanoFree™ Package
- Optimized for 1.8-V Operation and Is 3.6-V I/O Tolerant to Support Mixed-Mode Signal Operation
- I_{off} Supports Partial Power-Down-Mode Operation
- Sub-1-V Operable

- Max t_{nd} of 1.9 ns at 1.8 V
- Low Power Consumption, 10-μA Max I_{CC}
- ±8-mA Output Drive at 1.8 V
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Model (A114-B, Class II)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)



See mechanical drawings for dimensions.

DESCRIPTION/ORDERING INFORMATION

This single positive-edge-triggered D-type flip-flop is operational at 0.8-V to 2.7-V V_{CC} , but is designed specifically for 1.65-V to 1.95-V V_{CC} operation.

When data at the data (D) input meets the setup time requirement, the data is transferred to the Q output on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

NanoFree™ package technology is a major breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

ORDERING INFORMATION

T _A	PACKAGE ⁽¹⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING ⁽²⁾
	NanoFree [™] – WCSP (DSBGA) 0.23-mm Large Bump – YZP (Pb-free)	Reel of 3000	SN74AUC2G79YZPR	UR_
-40°C to 85°C	SSOP - DCT	Reel of 3000	SN74AUC2G79DCTR	U79
	VSSOP - DCU	Reel of 3000	SN74AUC2G79DCUR	U79_

⁽¹⁾ Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

⁽²⁾ DCT: The actual top-side marking has three additional characters that designate the year, month, and assembly/test site. DCU: The actual top-side marking has one additional character that designates the assembly/test site. YZP: The actual top-side marking has three preceding characters to denote year, month, and sequence code, and one following character to designate the assembly/test site. Pin 1 identifier indicates solder-bump composition (1 = SnPb, • = Pb-free).



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

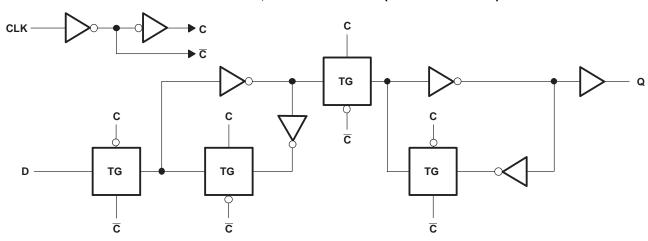
NanoFree is a trademark of Texas Instruments.



FUNCTION TABLE

INPU	JTS	OUTPUT
CLK	D	Q
1	Н	Н
\uparrow	L	L
L	X	Q_0

LOGIC DIAGRAM, EACH FLIP-FLOP (POSITIVE LOGIC)



Absolute Maximum Ratings(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	3.6	V
VI	Input voltage range ⁽²⁾		-0.5	3.6	V
Vo	Voltage range applied to any output in the h	nigh-impedance or power-off state ⁽²⁾	-0.5	3.6	V
Vo	Output voltage range ⁽²⁾		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		-50	mA
I _{OK}	Output clamp current		-50	mA	
Io	Continuous output current			±20	mA
	Continuous current through V _{CC} or GND			±100	mA
		DCT package		220	
θ_{JA}	Package thermal impedance (3)	DCU package		227	°C/W
		YZP package		102	
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

⁽²⁾ The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ The package thermal impedance is calculated in accordance with JESD 51-7.

DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP

SCES536C-DECEMBER 2003-REVISED JANUARY 2007

Recommended Operating Conditions⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage		0.8	2.7	V
		V _{CC} = 0.8 V	V _{CC}		
V_{IH}	High-level input voltage	$V_{CC} = 1.1 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$		V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		
		V _{CC} = 0.8 V		0	
V_{IL}	Low-level input voltage	V _{CC} = 1.1 V to 1.95 V		$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	
V_{I}	Input voltage		0	3.6	V
V_{O}	Output voltage		0	V_{CC}	V
		V _{CC} = 0.8 V		-0.7	
		V _{CC} = 1.1 V		-ვ	
I_{OH}	High-level output current	V _{CC} = 1.4 V		-5	mA
		V _{CC} = 1.65 V		-8	
		V _{CC} = 2.3 V		-9	
		V _{CC} = 0.8 V		0.7	
		V _{CC} = 1.1 V		3	
I_{OL}	Low-level output current	V _{CC} = 1.4 V		5	mA
		V _{CC} = 1.65 V		8	
		V _{CC} = 2.3 V		9	
		$V_{CC} = 0.8 \text{ V to } 1.65 \text{ V}^{(2)}$		20	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 1.65 \text{ V to } 2.3 \text{ V}^{(3)}$		20	ns/V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}^{(3)}$		20	
T _A	Operating free-air temperature		-40	85	°C

 ⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.
 (2) The data was taken at C_L = 15 pF, R_L = 2 kΩ (see Figure 1).
 (3) The data was taken at C_L = 30 pF, R_L = 500 Ω (see Figure 1).

SN74AUC2G79 DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP

SCES536C-DECEMBER 2003-REVISED JANUARY 2007



Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{cc}	MIN TYP ⁽¹⁾	MAX	UNIT
	$I_{OH} = -100 \mu A$	0.8 V to 2.7 V	V _{CC} - 0.1		
	$I_{OH} = -0.7 \text{ mA}$	0.8 V	0.55		
	$I_{OH} = -3 \text{ mA}$	1.1 V	0.8		V
V _{OH}	$I_{OH} = -5 \text{ mA}$	1.4 V	1		
	$I_{OH} = -8 \text{ mA}$	1.65 V	1.2		
	$I_{OH} = -9 \text{ mA}$	2.3 V	1.8		
	I _{OL} = 100 μA	0.8 V to 2.7 V		0.2	
	I _{OL} = 0.7 mA	0.8 V	0.25		
V	I _{OL} = 3 mA	1.1 V		0.3	V
V _{OL}	I _{OL} = 5 mA	1.4 V		0.4	V
	I _{OL} = 8 mA	1.65 V		0.45	
	I _{OL} = 9 mA	2.3 V		0.6	
I _I D or CLK inputs	$V_I = V_{CC}$ or GND	0 to 2.7 V		±5	μΑ
I _{off}	V_1 or $V_0 = 2.7 \text{ V}$	0		±10	μΑ
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	0.8 V to 2.7 V		10	μΑ
Ci	$V_I = V_{CC}$ or GND	2.5 V	2.5		pF

⁽¹⁾ All typical values are at $T_A = 25$ °C.

Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		V _{CC} = 0.8 V	V _{CC} = 1.2 V ± 0.1 V		V _{CC} = 1.5 V ± 0.1 V		V _{CC} = 1.8 V ± 0.15 V		V_{CC} = 2.5 V \pm 0.2 V		UNIT
		TYP	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency	50		200		225		250		275	MHz
t _w	Pulse duration, CLK high or low	2.4	1		1		1		1		ns
t _{su}	Setup time before CLK↑	1.6	0.9		0.6		0.6		0.5		ns
t _h	Hold time, data after CLK↑	0	0		0		0.1		0.1		ns

Switching Characteristics

over recommended operating free-air temperature range, C_L = 15 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (INPUT) (OUTPUT		_		V _{CC} = 1.2 V ± 0.1 V		V _{CC} = 1.5 V ± 0.1 V		V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		UNIT
	(IIVFOT)	(001701)	TYP	MIN	MAX	MIN	MAX	MIN	TYP	MAX	MIN	MAX	
f _{max}			50	200		225		250			275		MHz
t _{pd}	CLK	Q	5	1	3.9	0.8	2.5	0.3	1	1.9	0.3	1.3	ns

Switching Characteristics

over recommended operating free-air temperature range, $C_L = 30 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C	_C = 1.8	V /	V _{CC} = ± 0.	UNIT	
	(INFOI)	(001F01)	MIN	TYP	MAX	MIN	MAX	
f _{max}			250			275		ns
t _{pd}	CLK	Q	0.8	1.5	2.4	0.6	1.8	ns



SN74AUC2G79 DUAL POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP

SCES536C-DECEMBER 2003-REVISED JANUARY 2007

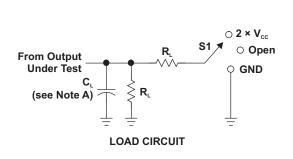
Operating Characteristics

 $T_A = 25^{\circ}C$

PARAMETER			TEST	$V_{CC} = 0.8 \text{ V}$	V _{CC} = 1.2 V	V _{CC} = 1.5 V	V _{CC} = 1.8 V	V _{CC} = 2.5 V	UNIT	
		CONDITIONS	TYP	TYP	TYP	TYP	TYP	•		
		Data	f = 10 MHz	16	16.2	18	19.8	29.2		
C_{pd}	C _{pd} Power dissipation capacitance	CLK		1.1	1.1	1.2	1.5	2.7	pF	
,	oapaonanoo	Total		17.1	17.3	19.2	21.3	31.9		

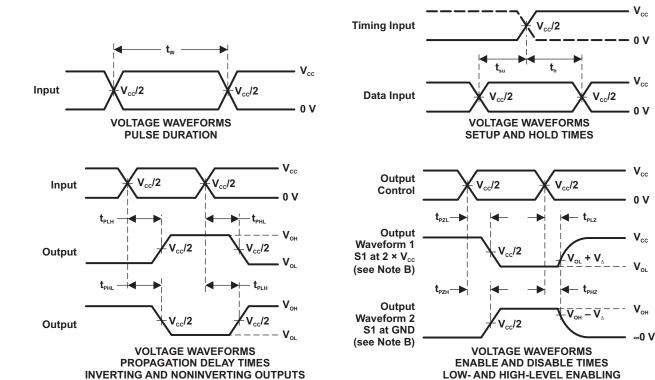


PARAMETER MEASUREMENT INFORMATION



TEST	S1
t _{PLH} /t _{PHL}	Open
t_{PLZ}/t_{PZL}	2 × V _{cc}
$t_{_{PHZ}}/t_{_{PZH}}$	GND

V _{cc}	C _∟	R _∟	V _Δ
0.8 V	15 pF	2 k Ω	0.1 V
1.2 V ± 0.1 V	15 pF	2 k Ω	0.1 V
1.5 V ± 0.1 V	15 pF	2 k Ω	0.1 V
1.8 V ± 0.15 V	15 pF	2 k Ω	0.15 V
$2.5~V~\pm~0.2~V$	15 pF	2 k Ω	0.15 V
1.8 V ± 0.15 V	30 pF	1 k Ω	0.15 V
2.5 V ± 0.2 V	30 pF	500 Ω	0.15 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_o = 50 Ω , slew rate \geq 1 V/ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. $t_{\text{\tiny PLZ}}$ and $t_{\text{\tiny PHZ}}$ are the same as $t_{\text{\tiny dis}}$
- F. $t_{\mbox{\tiny PZL}}$ and $t_{\mbox{\tiny PZH}}$ are the same as $t_{\mbox{\tiny en}}.$
- G. $t_{Pl\,H}$ and t_{PHl} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74AUC2G79DCTR	ACTIVE	SSOP	DCT	8	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 85	(2XD5, U79) (R, Z)	Samples
SN74AUC2G79DCUR	ACTIVE	VSSOP	DCU	8	3000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 85	(U79Q, U79R)	Samples
SN74AUC2G79YZPR	ACTIVE	DSBGA	YZP	8	3000	RoHS & Green	SNAGCU	Level-1-260C-UNLIM	-40 to 85	URN	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 5-Jan-2025

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AUC2G79DCTR	SSOP	DCT	8	3000	180.0	13.0	3.35	4.5	1.55	4.0	12.0	Q3
SN74AUC2G79DCUR	VSSOP	DCU	8	3000	178.0	9.5	2.25	3.35	1.05	4.0	8.0	Q3
SN74AUC2G79DCUR	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74AUC2G79YZPR	DSBGA	YZP	8	3000	178.0	9.2	1.02	2.02	0.63	4.0	8.0	Q1

www.ti.com 5-Jan-2025



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)			
SN74AUC2G79DCTR	SSOP	DCT	8	3000	182.0	182.0	20.0			
SN74AUC2G79DCUR	VSSOP	DCU	8	3000	202.0	201.0	28.0			
SN74AUC2G79DCUR	VSSOP	DCU	8	3000	202.0	201.0	28.0			
SN74AUC2G79YZPR	DSBGA	YZP	8	3000	220.0	220.0	35.0			





NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-187 variation CA.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.







NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.





NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.





DIE SIZE BALL GRID ARRAY



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



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